

# Electrical and optical properties III

Composites

# Outline

- Mixtures of two or more materials on the nano- or micro scale
- Metal-insulator mixtures most studied
- DC conductivity
- AC conductivity, percolation, fractals
- Optical properties, effective medium theories
- Light scattering

# Effective physical properties

- "Mixing rules" or effective medium theories
- Common description for:
- Optical and electrical properties (complex dielectric permittivity or refractive index)
- Magnetic permeability
- Thermal conductivity
- Mechanical properties (bulk and shear moduli)

# Two-phase composites

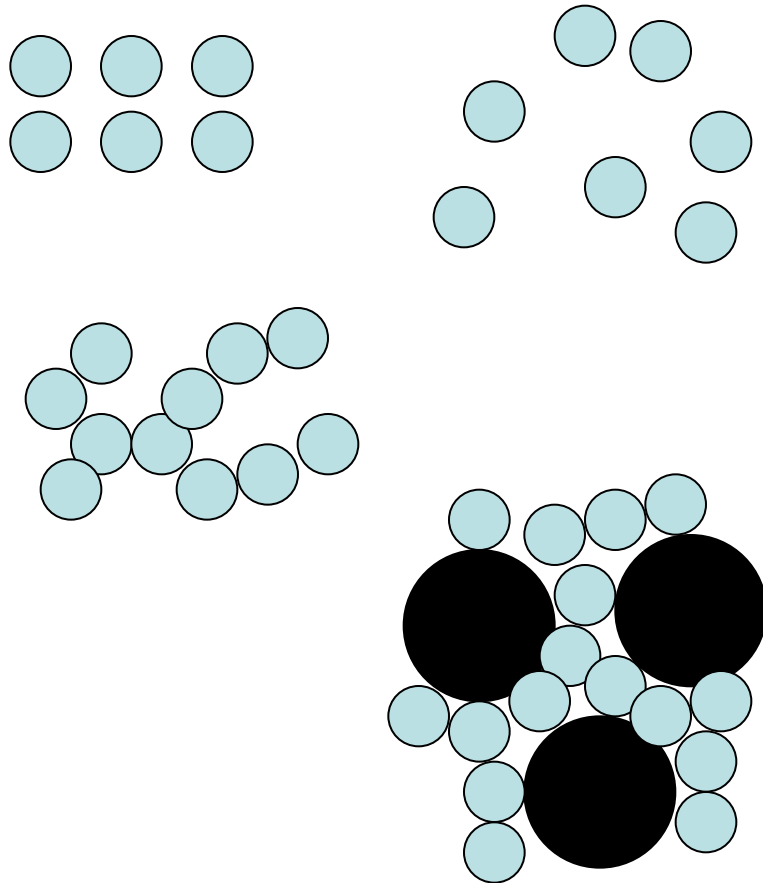
- Case of effective dielectric permittivity. The simplest mixing rule (phases A and B):

$$\bar{\epsilon} = f_A \epsilon_A + f_B \epsilon_B$$

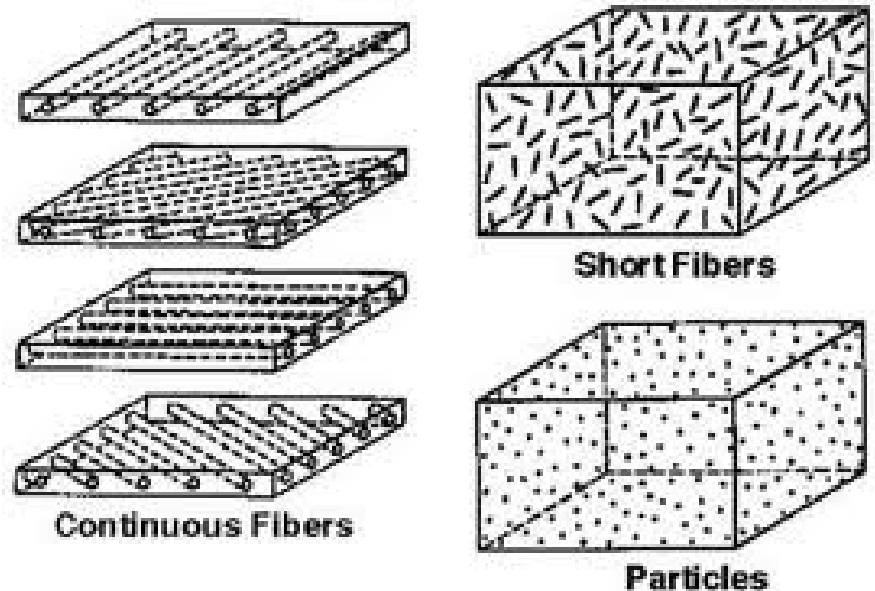
- Volume fractions of A and B:  $f_A, f_B$
- During the 1800's and early 1900's many such relations were derived
- Mosotti, Clausius, Maxwell, Lorenz, Lorentz, Rayleigh, Maxwell Garnett, Wiener, Wagner, Bruggeman...

# Microstructure in very important!

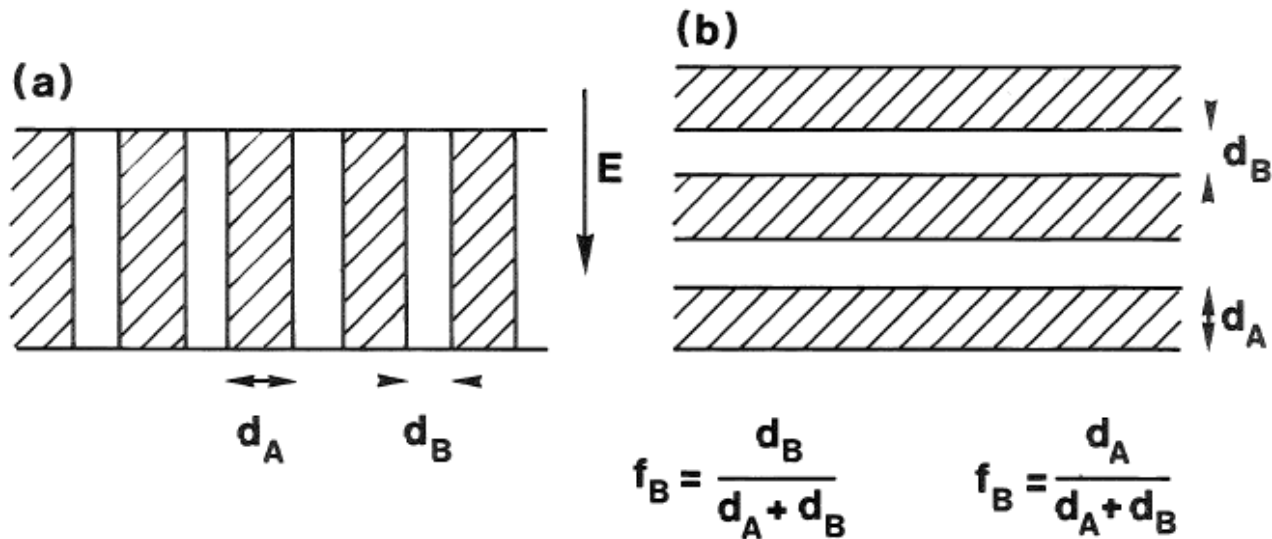
- Ordered and disordered



- Different particle shapes



# Rigorous Wiener bounds



- Parallel capacitors

$$\bar{\varepsilon} = f_A \varepsilon_A + f_B \varepsilon_B$$

- Series capacitors

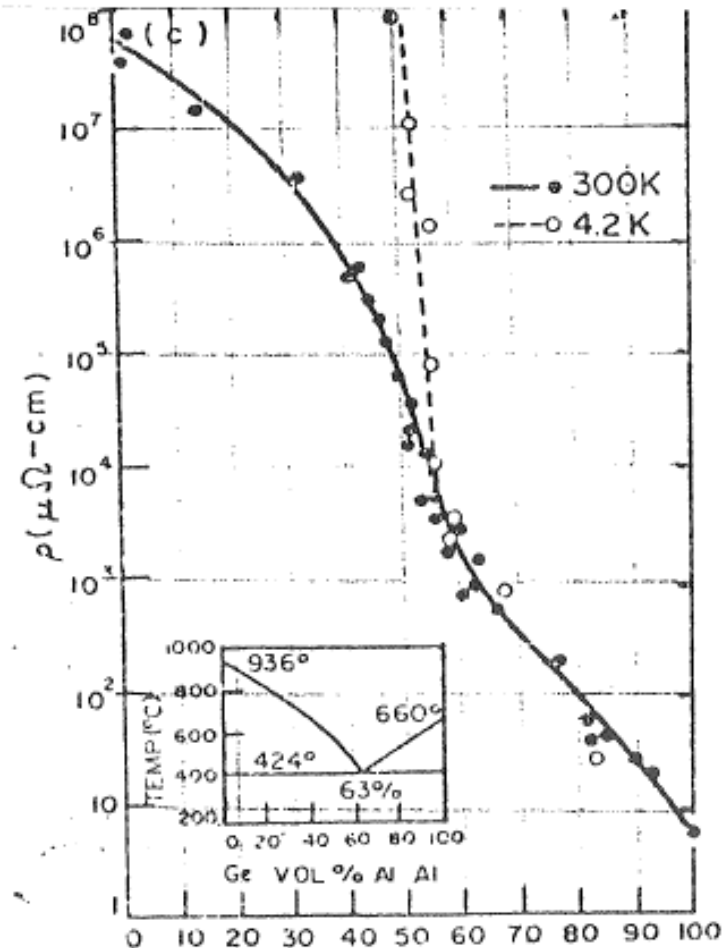
$$\bar{\varepsilon}^{-1} = f_A \varepsilon_A^{-1} + f_B \varepsilon_B^{-1}$$

# DC conductivity

- Composites from materials with widely differing resistivities
- Metal-insulator, metal-semiconductor
- By tailoring the composition every intermediate resistivity can be achieved
- Metal-insulator transition – percolation threshold
- Metallic conduction above the percolation threshold
- Tunneling between metal particles below the percolation threshold

# Ex: Al-Ge composites

- Low T – sharp metal-insulator transition at ~50 % Al
- High critical volume fraction – Ge tends to coat the Al particles
- Room temp. – we see a rising tunneling contribution below the transition



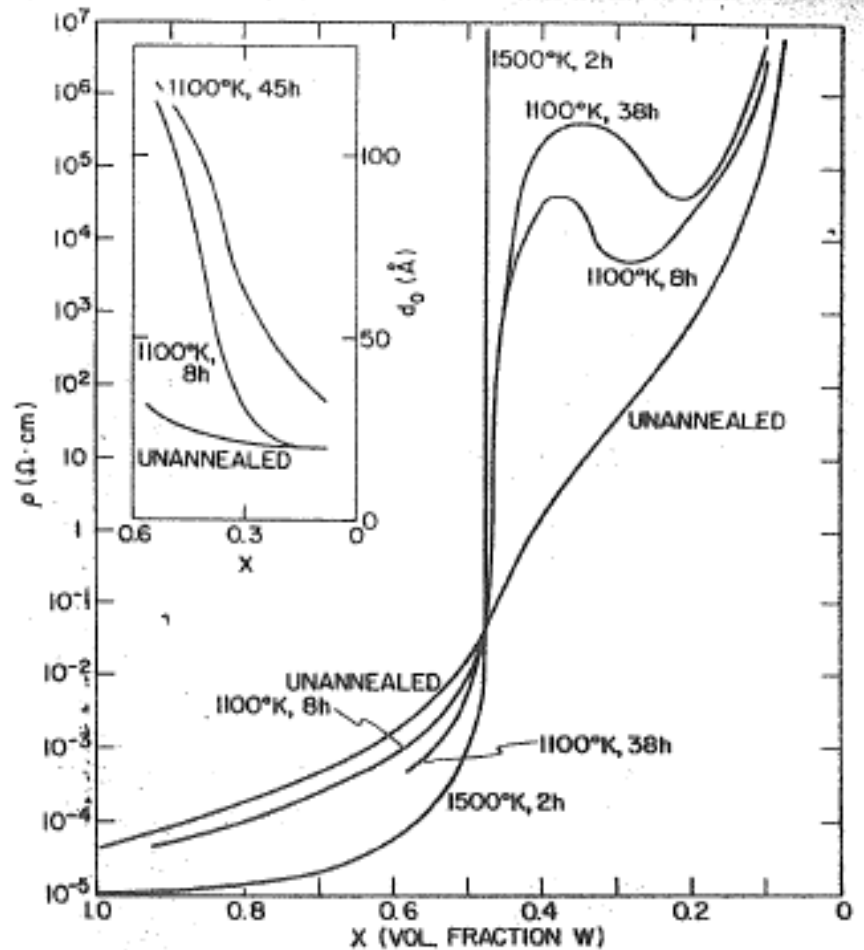
Source: Deutscher et al

$f_{\text{Al}}$



# Ex: W-Al<sub>2</sub>O<sub>3</sub> composites

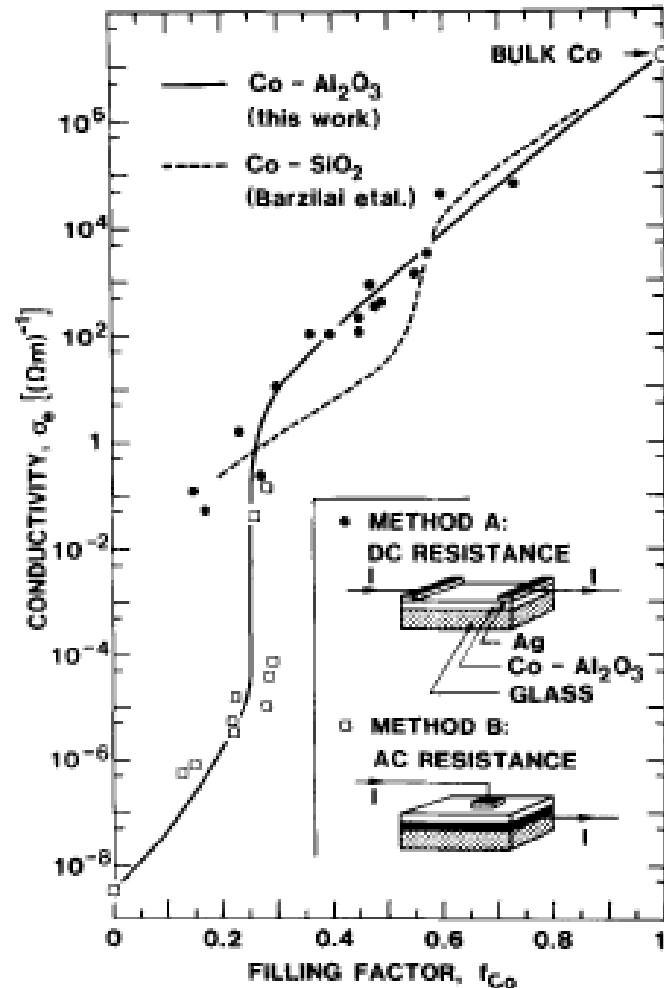
- Resistivity at T=300K
- Metal-insulator transition at  $f \sim 0.5$ . Insulator coats metal particles
- Annealing – particle size increases – larger separations between particles – much lower tunneling contribution – sharper transition
- Inset: W grain size



Source: Abeles et al

# Ex: Co-Al<sub>2</sub>O<sub>3</sub> composites

- Steep rise at  $f \sim 0.2$  to 0.3
- Connected with the tunneling contribution
- The temperature coefficient of resistance changes sign at  $f \sim 0.7$
- Smooth crossover between tunneling and metallic conduction



# Tunneling between metal particles

- Electron tunneling – the particles become charged
- Charging energy ( $s \sim r$ )

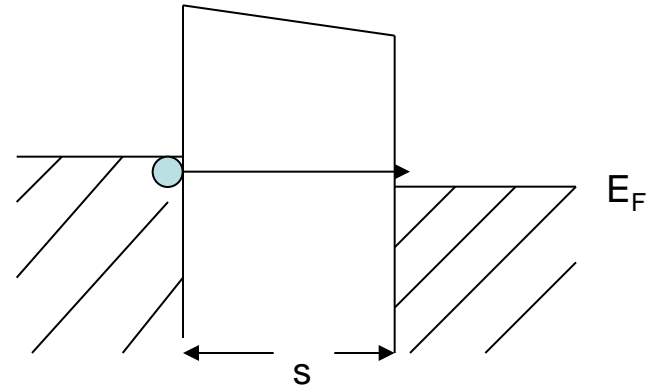
$$E_c = \frac{e^2}{4\pi\epsilon_0\epsilon_i} \frac{s/2r}{s+r} \sim C/s$$

- Low applied fields

$$\sigma = \sigma_0 \exp(-2\alpha s - E_c / k_B T)$$

- Max of  $\sigma$  when

$$s_M = (C / 2\alpha k_B T)^{1/2}$$



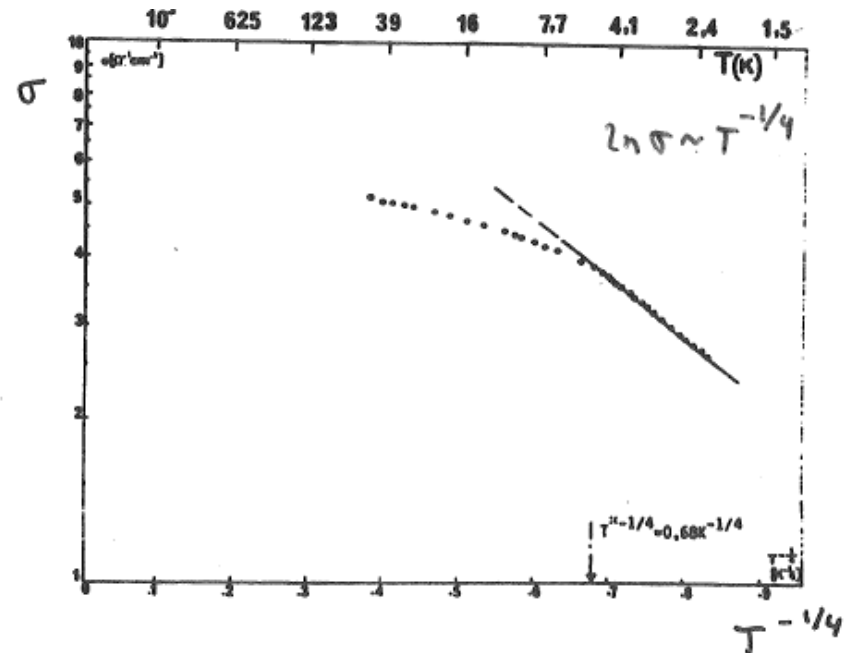
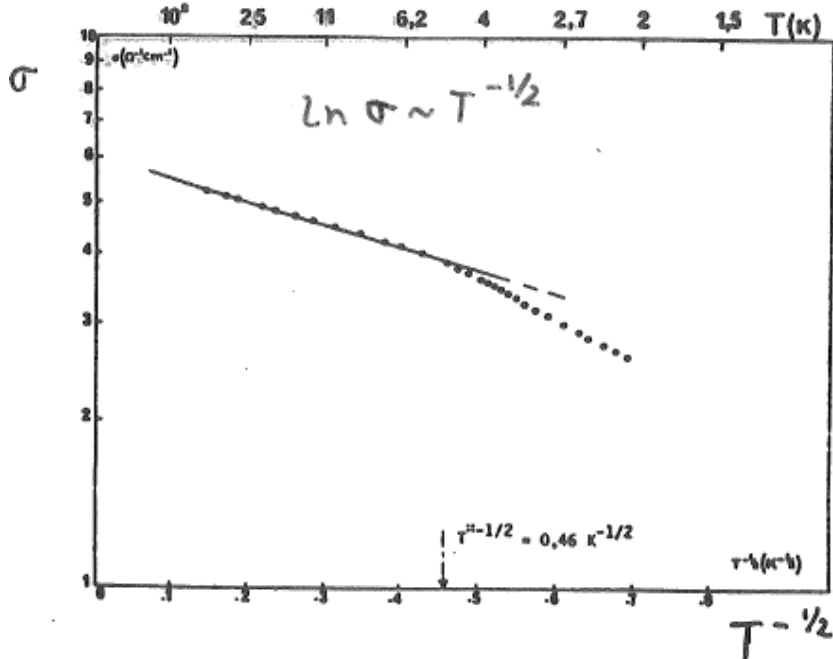
- Mott type expression

$$\sigma = \sigma_0 \exp(-(T_p / T)^{1/2})$$

- Different at very low temperatures

# Ex: Au-Al<sub>2</sub>O<sub>3</sub>

Experiments often show crossover to VRH behaviour



Source: Khatami, Thesis, 1985

# AC electrical properties

- Low  $f$  – insulating region: Particle-particle tunneling as well as localized states in the insulator
- Complex behaviour typical of insulators
- Intermediate  $f$ : Tunneling conductivity, "quasi-dc"
- High  $f$  – metallic region: Metallic conduction
- Metal-insulator crossover at the percolation threshold: Scaling behaviour as predicted by percolation theory

# Percolation theory: ac conductivity

- Metal-insulator composites: random structure of conducting and insulating regions
- Can be mapped onto a random RC-network
- Percolation theory: DC conductivity and dielectric constant close to the percolation threshold,  $f_c$

$$\sigma_{DC} \sim (f - f_c)^t \quad \epsilon_{DC} \sim |f - f_c|^{-s}$$

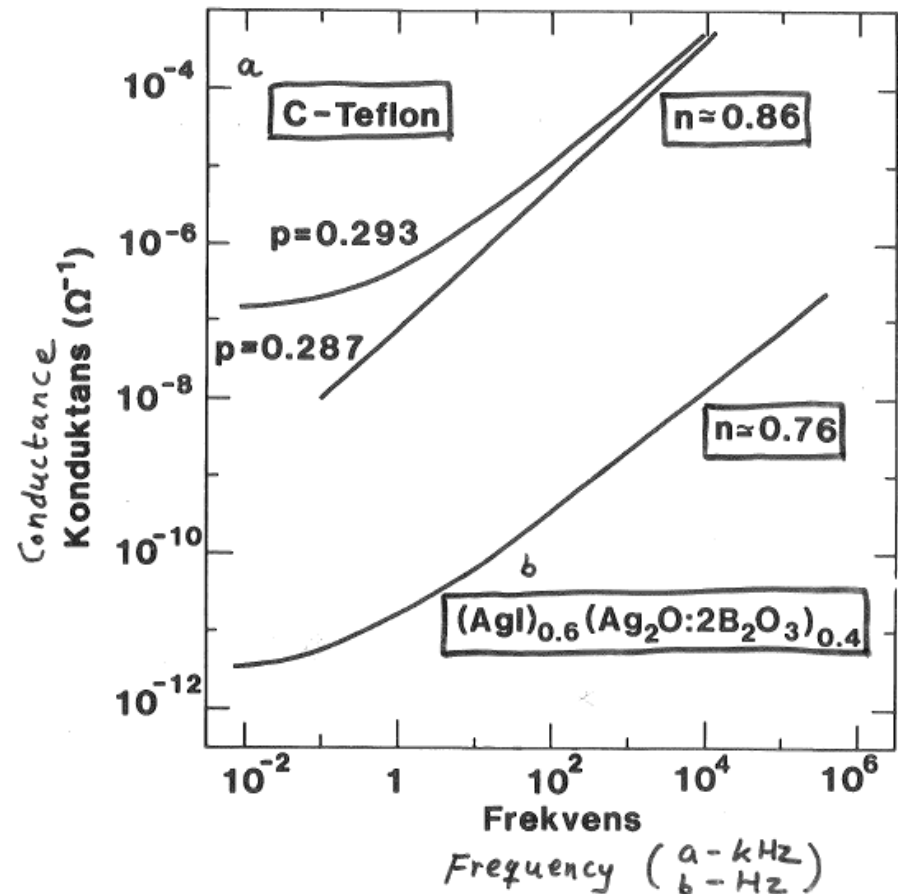
- Percolation theory: Frequency dependence

$$\sigma(\omega) \sim \omega^{t/(t+s)} \quad , \omega \gg \sigma_m |f - f_c|^{t+s} / \epsilon_i$$

# Experiments on composites

- Critical exponents (theory)
- $t = 1.9 \pm 0.1$
- $s = 0.73 \pm 0.01$
- $u = t/t+s = 0.72 \pm 0.02$
- Frequency exponent  $u$  is influenced by distributions of resistances and Coulomb interactions

Data from: Song et al; Brantervik et al.



# Optical properties

- We consider two component materials
- If the particle size  $\ll$  wavelength of light then the **E**- and **H**-fields are almost constant over a length of the order of a particle size
- Materials treated as homogeneous on length scales  $\sim \lambda$
- Quasistatic approximation (electrostatics sufficient for small particles)
- Basis of effective medium theories (EMT)



# Spheres in continuous matrix

- Consider dielectric function (permittivity)
- Static case ( $\omega=0$ )
- Quasistatic approx:
- Can be extended to frequency dependent case as long as  $\max(n) 2\pi r/\lambda \ll 1$  where  $\max(n)$  is the largest of the refractive indices

- Particles of A in matrix B
- Electric field

$$E_A = E_B + E_p = E_B - P/3\epsilon_0$$

- Compare the average fields  $E_{av}$  and  $D_{av}$
- The effective dielectric permittivity is given as (Maxwell, 1872)

$$\bar{\epsilon} = D_{av} / E_{av}$$

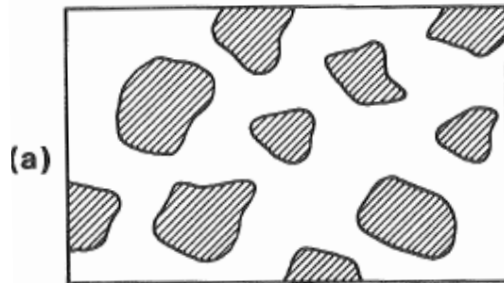
# Complex dielectric function

- Optical transmittance and reflectance depends on the effective complex and frequency-dependent dielectric function
- Different microstructures lead to different expressions for the complex  $\varepsilon$
- Microstructural models: Random Unit Cells
- Limit theorems give bounds in the complex plane
- Influence of microstructure can be represented by a spectral density.

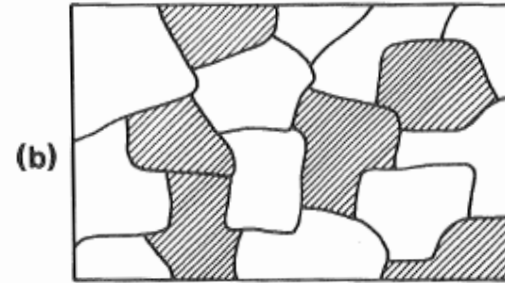
# Random Unit Cells (RUC)

- Two often used simple cases:

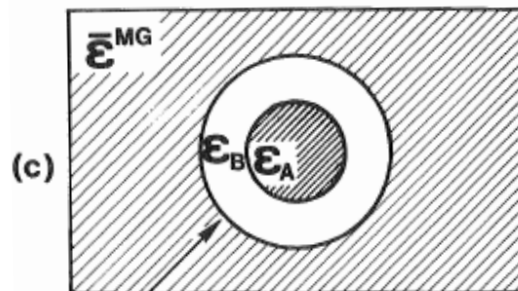
**Separated-grain structure**



**Aggregate structure**

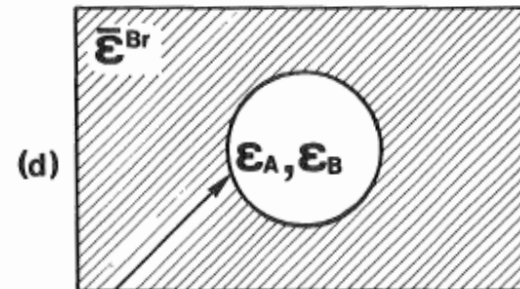


**Maxwell Garnett theory**



Ratio of volumes  
determines  $f$

**Bruggeman theory**



Probability  $f$  of being "A"  
Probability  $1-f$  of  
being "B"

# Derivation of EMT's

- RUC's can be used to systematically derive EMT's
- They account for the important aspects of a given microstructure
- Can be extended to nonspherical shapes
- Criterion: The RUC should be invisible in an optical experiment when embedded in the effective medium
- Light scattering  $S=0$
- Maxwell Garnett:  $S(\text{coated sphere})=0$
- Bruggeman:  $f_A S_A(\text{sphere}) + f_B S_B(\text{sphere}) = 0$
- Rule of thumb:  $r \ll \lambda/20$

# Some simple EMT's

- Maxwell Garnett (MG) theory

$$\bar{\varepsilon} = \varepsilon_B \frac{\varepsilon_A + 2\varepsilon_B + 2f_A(\varepsilon_A - \varepsilon_B)}{\varepsilon_A + 2\varepsilon_B - f_A(\varepsilon_A - \varepsilon_B)}$$

- Particles in continuous matrix (often amorphous)
- No percolation threshold
- Can be extended by incorporating information from pair distribution function

- Bruggeman (BR) theory

$$f_A \frac{\varepsilon_A - \bar{\varepsilon}}{\varepsilon_A + 2\bar{\varepsilon}} + (1 - f_A) \frac{\varepsilon_B - \bar{\varepsilon}}{\varepsilon_B + 2\bar{\varepsilon}} = 0$$

- Random mixtures of A and B
- Percolation threshold  $f_c = 1/3$  for spheres
- Different for other shapes
- If RUC's are coated spheres:  $f_c = 0.50$

# Physical interpretation

- Mixture of metal and insulator nanocrystals: Random distribution – **BR theory**. Not good close to  $f_c$ , which should be at  $\sim 0.15$ .
- Insulator crystallites  $\ll$  metal ones: They will preferentially be situated between the metal particles, and hence  $f_c$  increases.
- Metal nanocrystals and amorphous insulator: Metal particles preferentially coated by insulator. **MG theory** is a good approximation at low  $f$ , and we have a high  $f_c$

# Rigorous bounds on complex $\varepsilon$

- Wiener bounds: Only  $\varepsilon_A$  and  $\varepsilon_B$  known

$$\bar{\varepsilon} = f_A \varepsilon_A + f_B \varepsilon_B \quad \bar{\varepsilon}^{-1} = f_A \varepsilon_A^{-1} + f_B \varepsilon_B^{-1}$$

- Arcs/lines in the complex plane encompassing an allowed region
- Hashin-Shtrikman bounds: Also  $f_A$  and  $f_B$  known

$$\bar{\varepsilon} = \varepsilon_B \frac{L\varepsilon_A + (1-L)\varepsilon_B + (1-L)f_A(\varepsilon_A - \varepsilon_B)}{L\varepsilon_A + (1-L)\varepsilon_B - Lf_A(\varepsilon_A - \varepsilon_B)} \quad 0 \leq L \leq 1$$

$$\bar{\varepsilon} = \varepsilon_A \frac{L\varepsilon_B + (1-L)\varepsilon_A + (1-L)f_B(\varepsilon_B - \varepsilon_A)}{L\varepsilon_B + (1-L)\varepsilon_A - Lf_B(\varepsilon_B - \varepsilon_A)}$$

# Bounds for isotropic materials

- More narrow bounds still (Bergman-Milton)

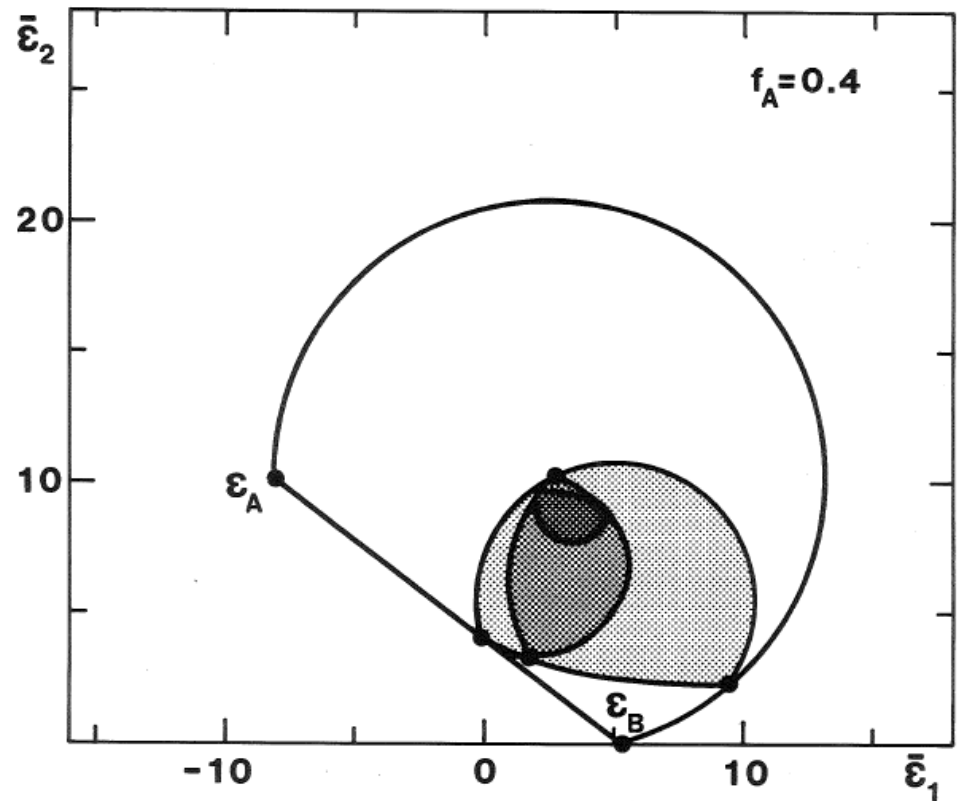
$$\bar{\varepsilon} = \frac{\varepsilon_A \varepsilon_B + 2\varepsilon_h (f_A \varepsilon_A + f_B \varepsilon_B)}{2\varepsilon_h + f_A \varepsilon_B + f_B \varepsilon_A} \quad \varepsilon_h = x\varepsilon_A + (1-x)\varepsilon_B \quad \text{or}$$
$$\varepsilon_h^{-1} = x\varepsilon_A^{-1} + (1-x)\varepsilon_B^{-1}$$

- The parameter  $x$  ( $0 \leq x \leq 1$ ) can be obtained from integrals over the pair and three-point distribution functions of the composite
- If  $x$  is known – another set of bounds and so on...



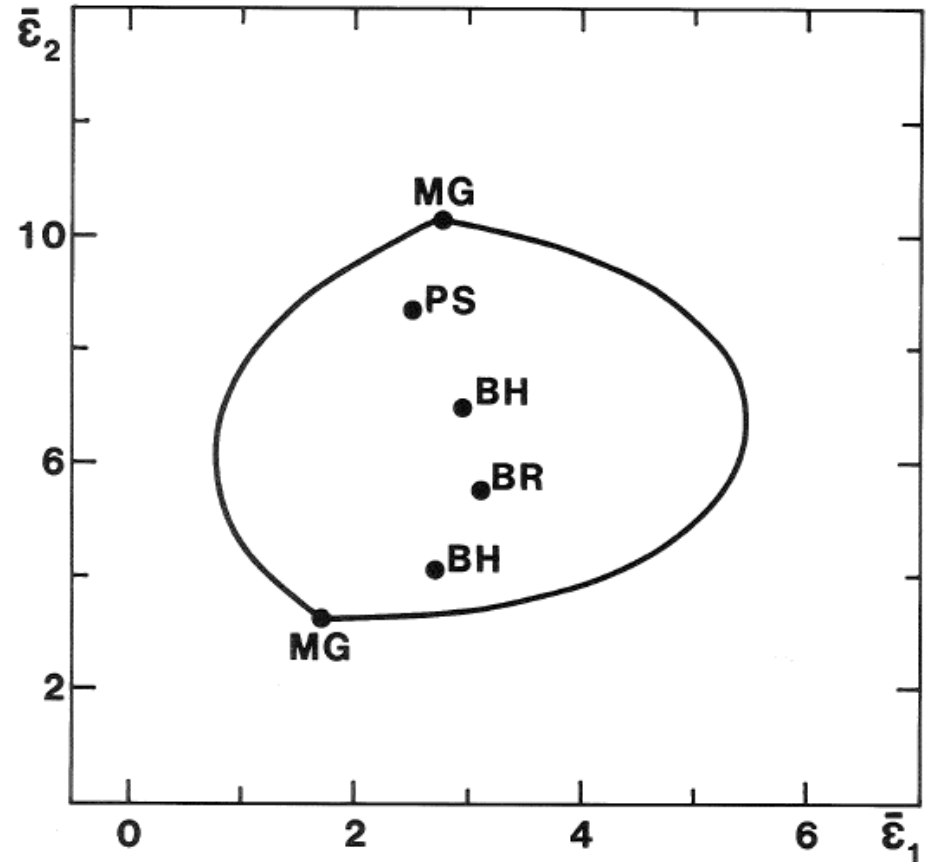
# Example of bounds

- $\varepsilon_A$  and  $\varepsilon_B$  given
- Wiener bounds
- HS bounds (anisotropic in general)
- BM bounds (isotropy)
- Next order bounds with  $x=0.1$



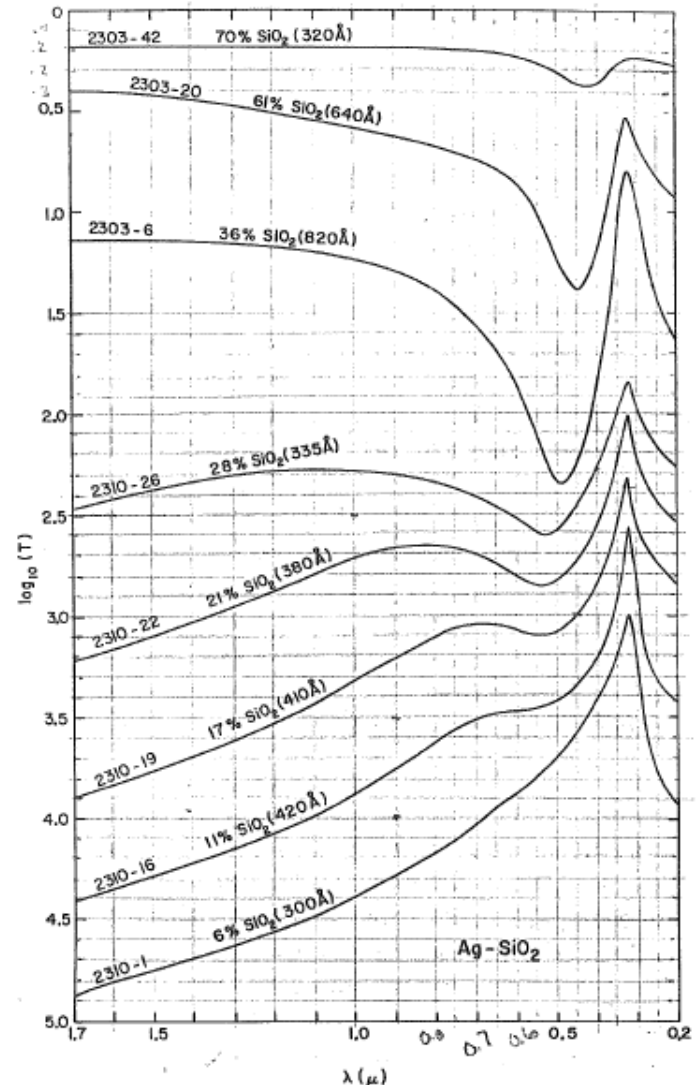
# Isotropic materials

- Isotropic bounds and some EMT's
- Input values as in previous figure
- MG – Maxwell Garnett
- BR – Bruggeman
- PS – Ping Sheng (BR for coated spheres)
- BH - Bruggeman-Hanai



# Exp: Transmittance

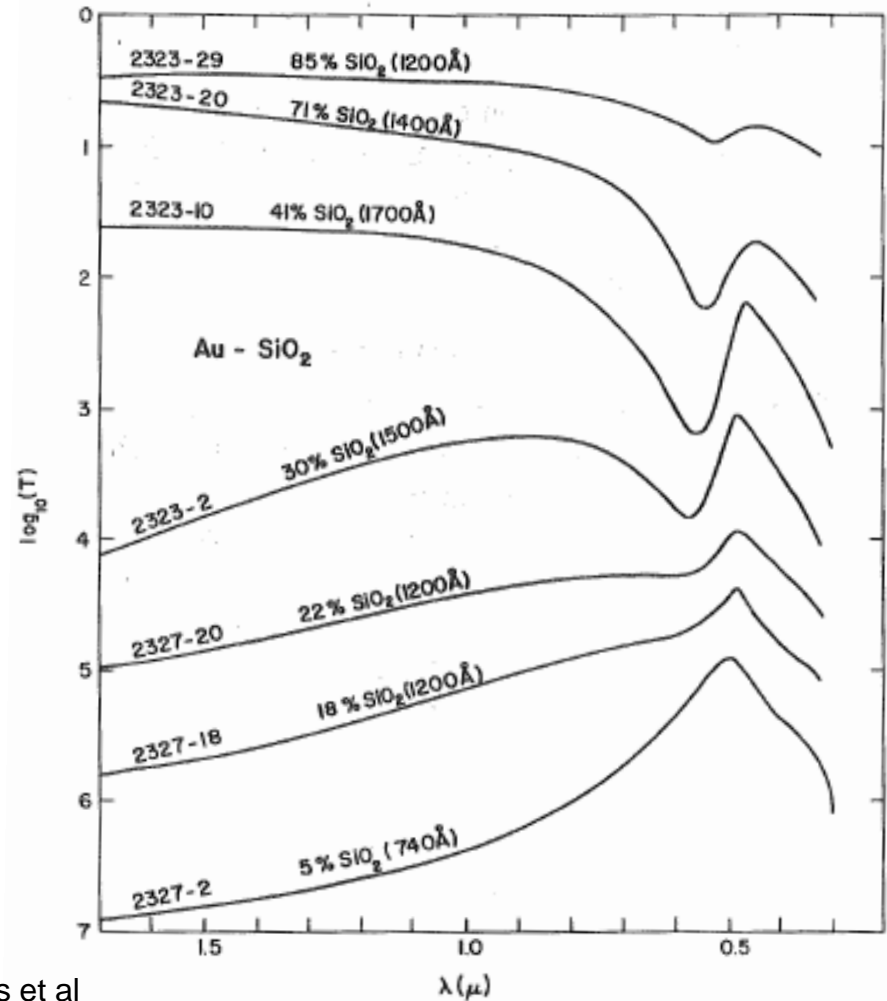
- Clear-cut case: Noble metal composites
- Ex: Ag- SiO<sub>2</sub>
- Metallic behaviour: <25 % SiO<sub>2</sub>
- Dielectric behaviour: >35 % SiO<sub>2</sub>
- Localized plasmon (LP) absorption at  $\lambda \sim 400\text{-}500$  nm
- Sharp LP predicted by MG theory



Source: Abeles et al

# Ex: Au-SiO<sub>2</sub>

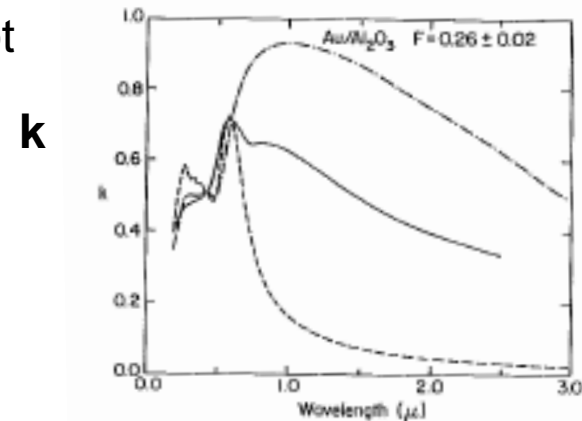
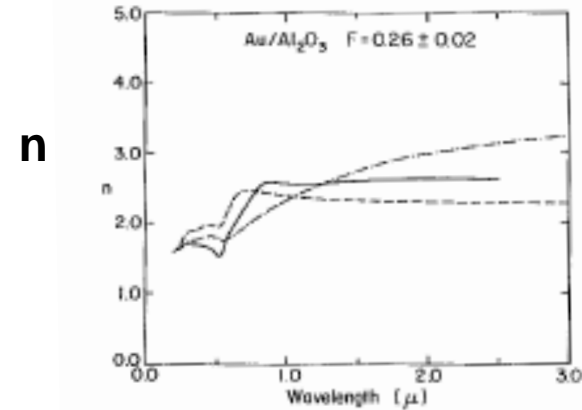
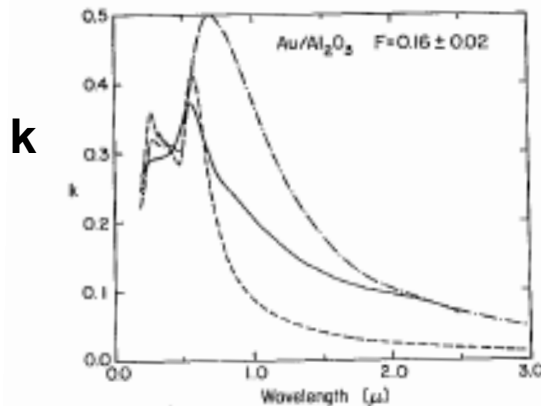
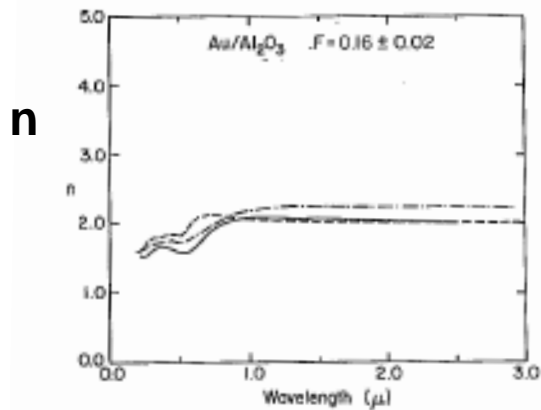
- Dielectric and metallic regions
- Metal-insulator transition around  $f_{Au} \sim 0.6$  to  $0.7$
- Localized plasma absorption at 500-600 nm
- Diminishes in the metallic region
- Percolation threshold higher than most theories predict (PS at  $\sim 0.5$  may be OK)



Source: Abeles et al

# Exp: Dielectric function

- Au-Al<sub>2</sub>O<sub>3</sub> (amorphous)
- $\epsilon=(n+ik)^2$

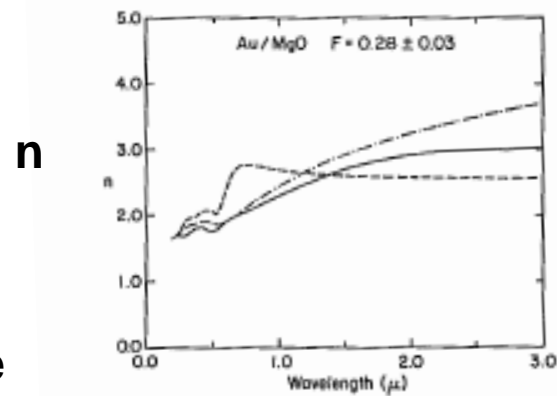
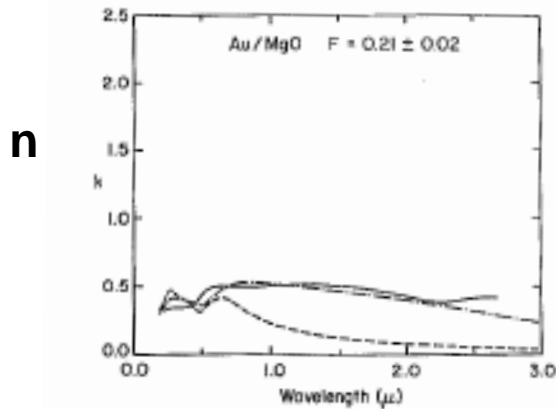


Exp-full line  
MG-dash  
BR-dash-dot

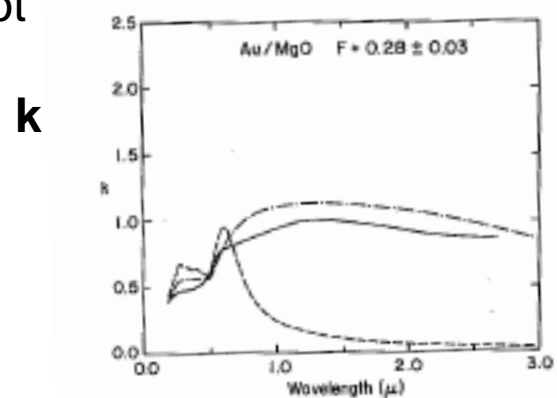
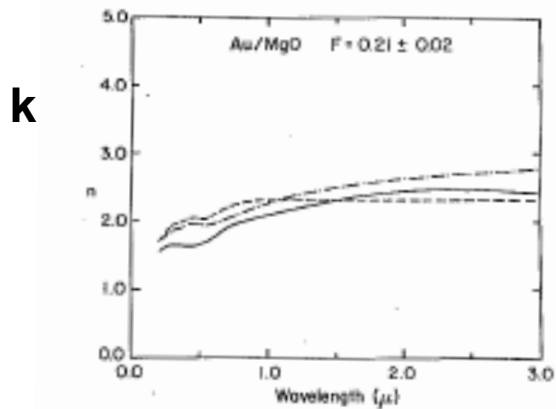
# Ex: Au-MgO

- Mixture of nanocrystals

- $\epsilon=(n+ik)^2$

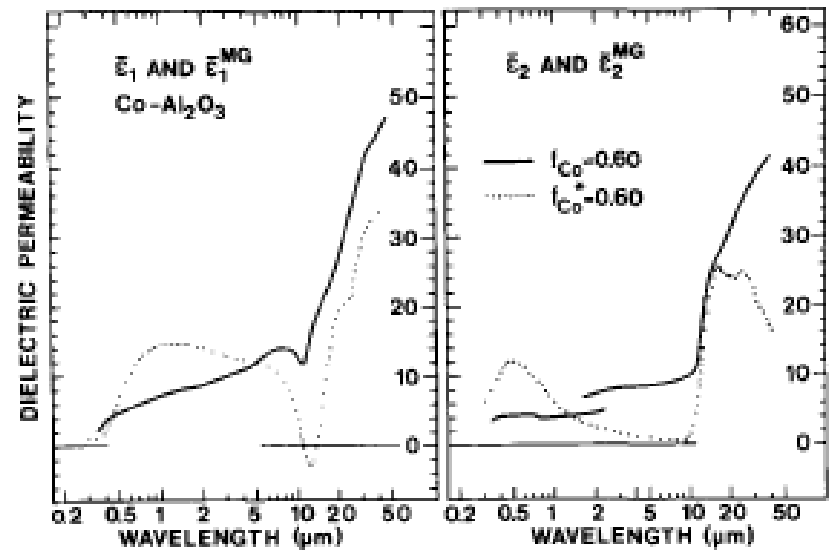
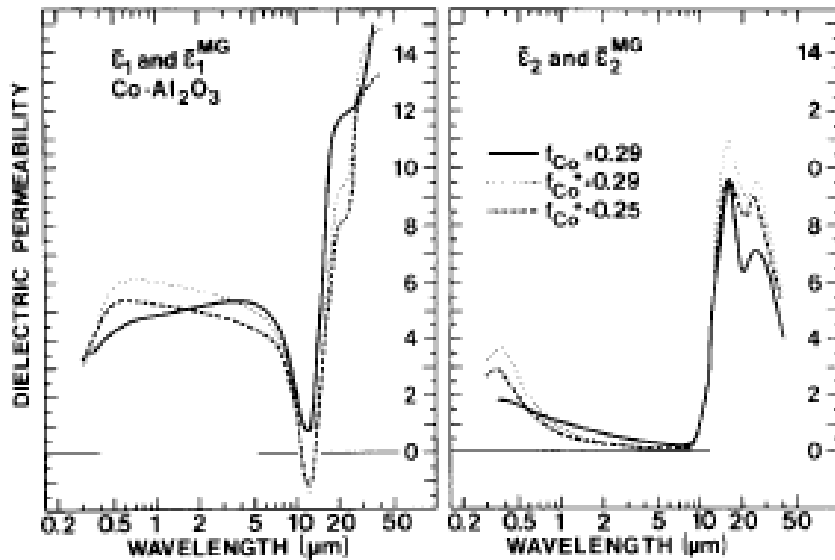


Exp-full line  
MG-dash  
BR-dash-dot



# Ex: Co-Al<sub>2</sub>O<sub>3</sub>

- Small f: MG quite good
- Vis-NIR-IR data



# Transition region

- The distinction between MG and BR type composites is very useful for the dielectric region at low  $f$ .
- EMT's do not give a good description of the percolation region: Difficult to model  $\exp f_c$  and critical exponents are not correct in BR theory
- Close to  $f_c$  the percolation correlation length can be  $>\lambda$  and then the effective medium concept will fail.
- "Optical percolation": Descriptions with scaling theories, fractal impedance networks or general LCR networks have been attempted.



# Bergman's spectral density

- It is possible to decouple the effect of nanostructure on the dielectric function from the properties of the phases A and B

$$\bar{\varepsilon} = \varepsilon_B \left( 1 + \int_0^1 \frac{g(x)}{(\varepsilon_B / (\varepsilon_A - \varepsilon_B)) + x} dx \right)$$

- Sum rules for the spectral density  $g(x)$

$$g(0) + \int_{0^+}^1 g(x) dx = f_A \quad \int_0^1 xg(x) dx = (1 - f_A)L$$

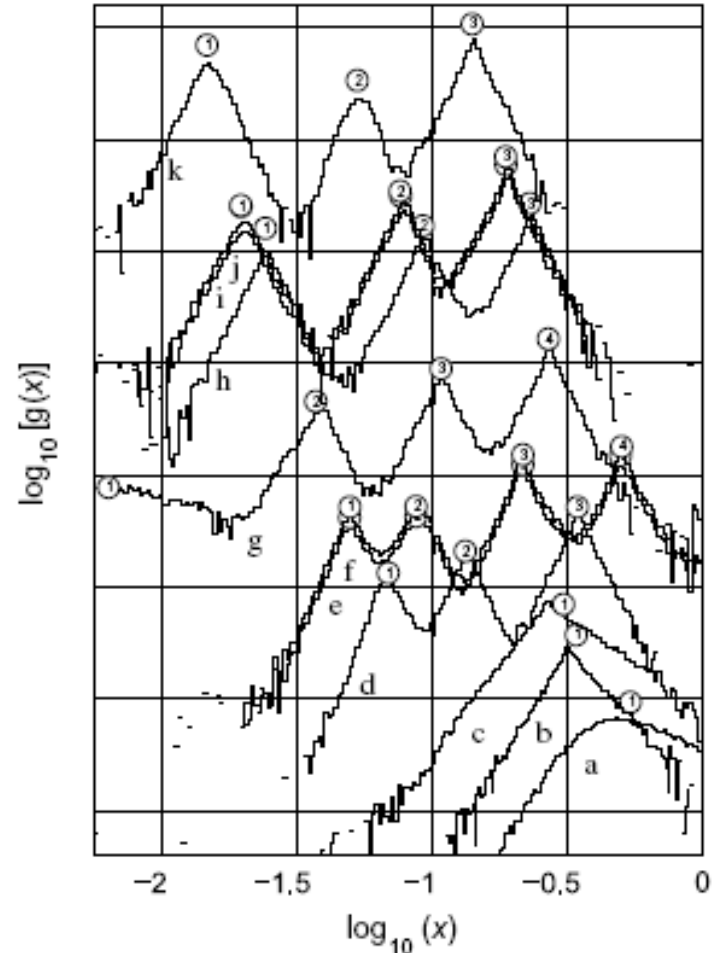
- We have separated out the percolation strength  $g(0)$
- But relation between  $g(x)$  and nanostructure not known!

# Spectral density function (SDF)

- This relation is in principle "exact" and  $g(x)$  is determined by the detailed nanostructure.
- The SDF  $g(x)$  can only be computed if the nanostructure is known exactly
- Even so it is not known how to compute it, except in simple cases
- It is however possible to obtain  $g(x)$  from inversion of experimental data (dielectric function from R,T or ellipsometry) in a wide wavelength range
- Exp. data sensitive to  $g(x)$  when the real part of  $\epsilon_A$  is negative and its absolute value is larger than that of the imaginary part

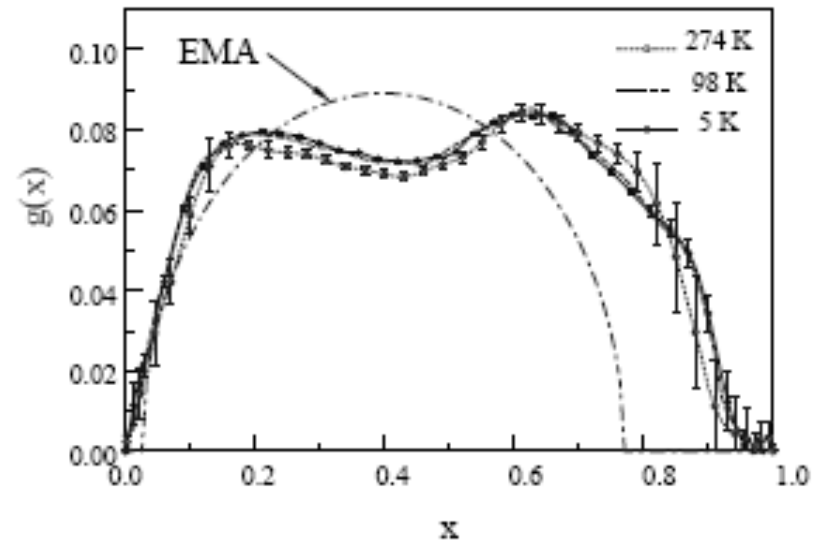
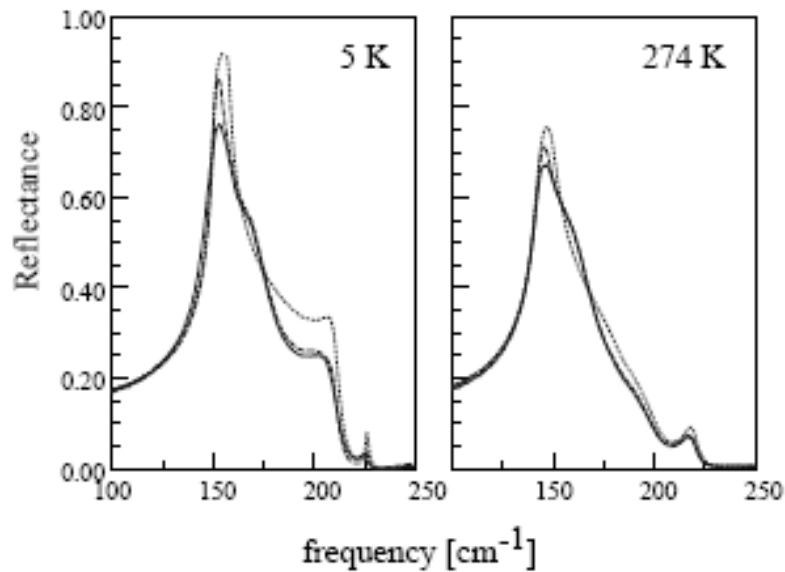
# Ex: Co-Al<sub>2</sub>O<sub>3</sub> composite

- From R and T measurements:  
 $300 \text{ nm} < \lambda < 2500 \text{ nm}$
- Volume fractions of Co, f:  
a:0.03, b:0.07, c:0.12, d:0.19,  
e:0.25, f:0.26, g:0.37, h:0.52,  
i:0.56, j:0.57, k:0.71.
- Low f: Peak corresponding to almost spherical particles
- $f > 0.15$ : Three or four peaks (structural resonances)
- Percolation strength cannot be reasonably estimated from optical data



# Ex: KCl-diamond composite

- 20 % Diamond
- IR reflectance
- SDF compared to Bruggeman theory
- $x g(x)$  is plotted



# A general effective medium theory?

- Use description of nanostructure in terms of local density distributions and local percolation probabilities
- Generalization of Bruggeman theory:

$$\int_0^1 \left[ \lambda(f, L) \frac{\varepsilon_c(f) - \bar{\varepsilon}}{\varepsilon_c(f) + 2\bar{\varepsilon}} + (1 - \lambda(f, L)) \frac{\varepsilon_{nc}(f) - \bar{\varepsilon}}{\varepsilon_{nc}(f) + 2\bar{\varepsilon}} \right] \mu(f, L) df = 0$$

- Evaluate for L where the entropy function has a minimum
- Percolating cells – index c
- Non-percolating cells – index nc
- $L \rightarrow 0$ : Usual Bruggeman expression
- $L \rightarrow \text{infinity}$ : No L-dependence; replace f by  $\langle f \rangle$
- Percolation threshold determined by  $\lambda(f, L)$  or  $\lambda(\langle f \rangle)$

# Some applications

- Selectively solar absorbing coatings for solar collectors: Transition metal particles in an insulator matrix, high  $f$  ( $\sim 0.5$ )
- Modeling of rough surfaces, e.g. in ellipsometry
- Columnar structures or "sculptured" thin films: Extension of EMT's to anisotropic structures
- High voltage insulation – field grading materials
- C-black and C-fiber composites (electrical properties)
- Thermal insulation
- Porous materials: Geological applications, cement